nexperia

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023 Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number BZT52H-C8V2-Q Part Description									
							Nexperia DHAM	Zener			
							SMD package				
		Test Conditions	Duration	# Lots	# Quantity	# Rejects					
			TEST								
			Pre- and Post-Stress								
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below					
		JESD22-A113									
		Bake Tamb = 125 °C	24 hours								
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours		<i></i>						
# A1	Preconditioning	Reflow soldering	3 cycles	1514	64430	0					
		MIL-STD-750-1									
	HTRB	M1038 Method A Tj = Tjmax, VR = 80 % of rated reverse									
# B1	Bias	voltage	1000 hours	250	11400	0					
# DI	Did3	MIL-STD-750-1	1000 110015	230	11400	0					
		MIL-STD-750-1 M1038 Method B									
	SSOP	$T_j = T_j max$, $I_z = 100\%$ of max. datasheet									
# B1b	Steady State Operational	reverse current	1000 hours	44	1920	0					
	· · · · ·										
	тс	JESD22-A104									
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	311	14080	0					
	UHAST	JESD22-A118									
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %	96 hours	311	14080	0					
		JESD22-A102									
	AC	Tamb = 121 °C, RH = 100 %									
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)									
		150000 4141									
	H3TRB	JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of									
# AD - It	High Humidity High Temperature Reverse Bias		1000 hours	211	14000	0					
# A2 alt	remperature Reverse Dids		1000 hours	311	14080	0					
	IOL	MIL-STD-750 Method 1037									
# A5	Intermittent Operating Life	ton = toff, devices powered to insure ΔT_j = 100 °C for 15000 cycles	1000 hours	312	14120	0					
π AJ	Internitient operating Life		1000 110015	512	14120	U					
	RSH	JESD22-A111									
# C8	Resistance to Solder Heat	$260 \text{ °C} \pm 5 \text{ °C}$	10 s	269	8070	0					
	SD		200	205		<u> </u>					
# C10	Solderability	J-STD-002		19	6660	0					
						-					

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

2,68E+09
_

© 2024 Nexperia B.V.

All information hereunder is per Nexperia's best knowledge. This document does not provide for any representation or warranty express or implied by Nexperia. In case Nexperia has tested the product, this documentation reflects the outcome of the analysis of the actually tested parts only.

nexperia.com